

ELaboration of NANOmaterials for the recovery, conversion, transport and storage of energy

11-16 Jun 2023 Aussois (73500) (France)

Pulsed laser deposition

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N A M e

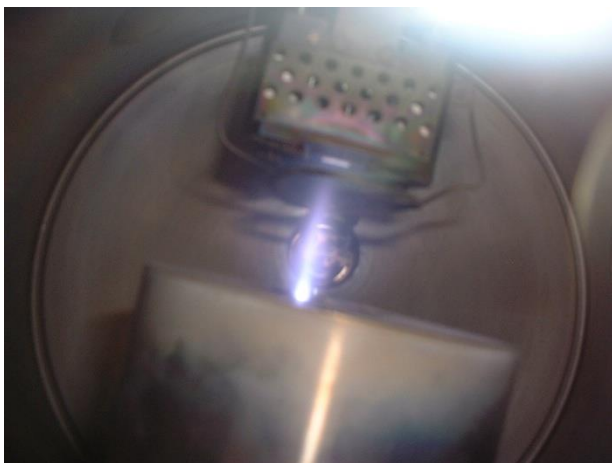
GDR Nanomaterials for Energy Applications

El Nano 11-16 june 2023

Thin film preparation

Laser ablation via a pulsed laser and deposition

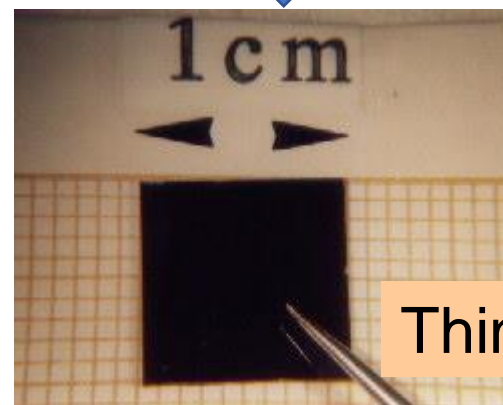
Target



deposition



substrate



Thin film

PULSED LASER DEPOSITION EVOLUTION

Sixties : the “ laser age ”

1960 : paper of T.H. Maimon (ruby laser)

1965 : first thin films : *H.M. Smith, A.F. Turner, Appl. Opt.*, **4**, 147 (1965)

CdTe, PbTe, ZnTe ... : under vacuum (10^{-4} Torr), ruby laser, 1 ms pulses

1968 : metals, oxides (BaTiO_3) ...*H. Schwarz, H.A. Tourtelotte, J. Vac. Sci. Technol.*, **6**, 373 (1968)

Seventies : short pulses lasers, peak power $> 10^6$ W

⇒ congruent evaporation : possibility to grow thin films with the same composition and the same structure as the starting target

J. Desserre, J.F. Eloy, Thin Solid Films, **29**, 29 (1975) (CdTe...)

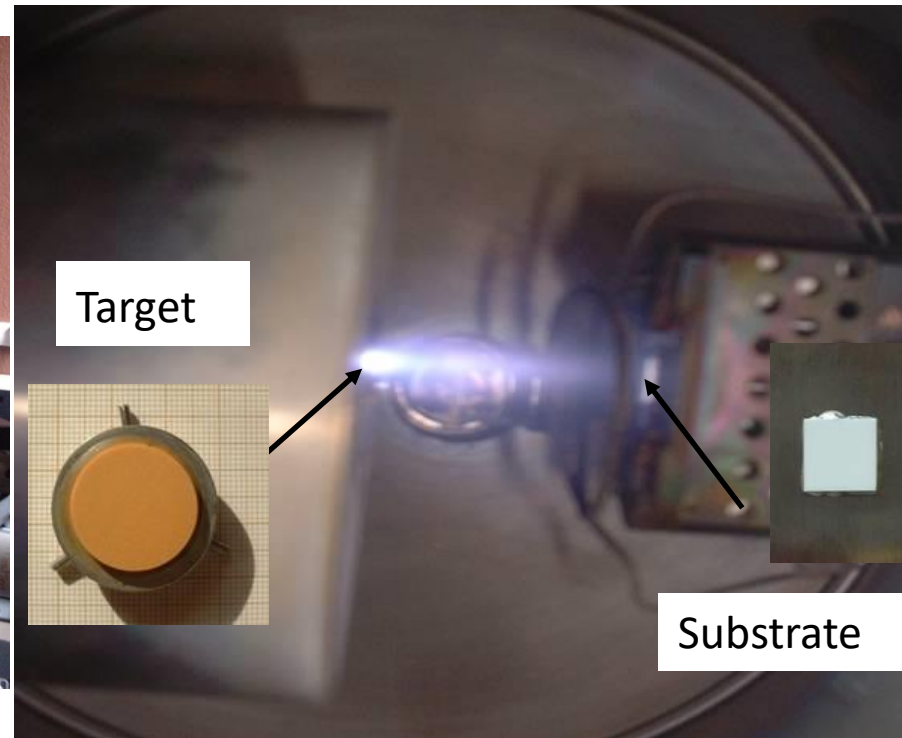
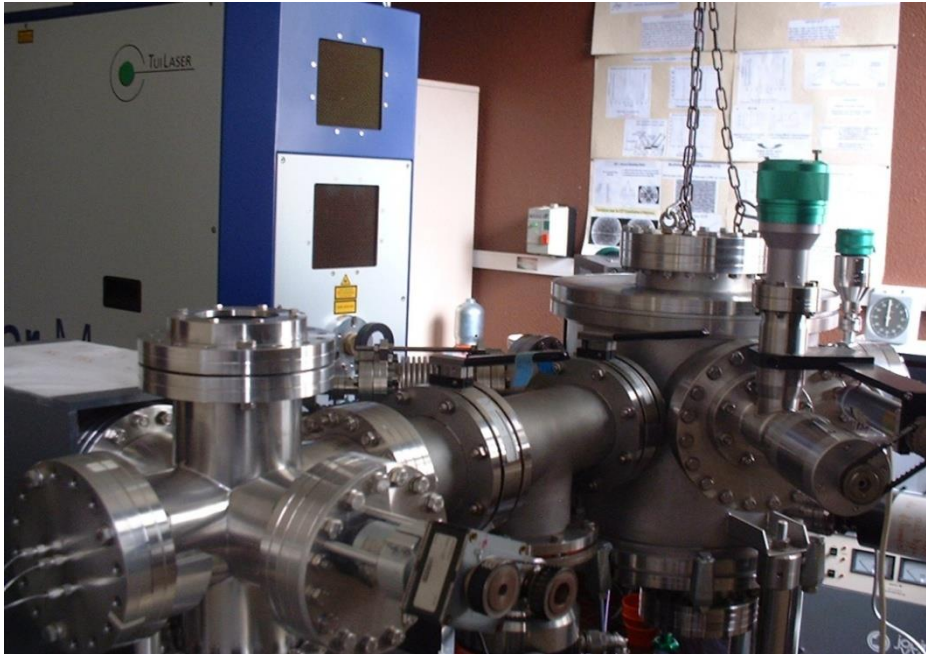
Eighties : short wavelengths (UV excimers) , high power pulses ...

advantages of PLD : versatility, congruence ...

Oxides : first high quality films of $\text{YBa}_2\text{Cu}_3\text{O}_7$ as soon as 1987

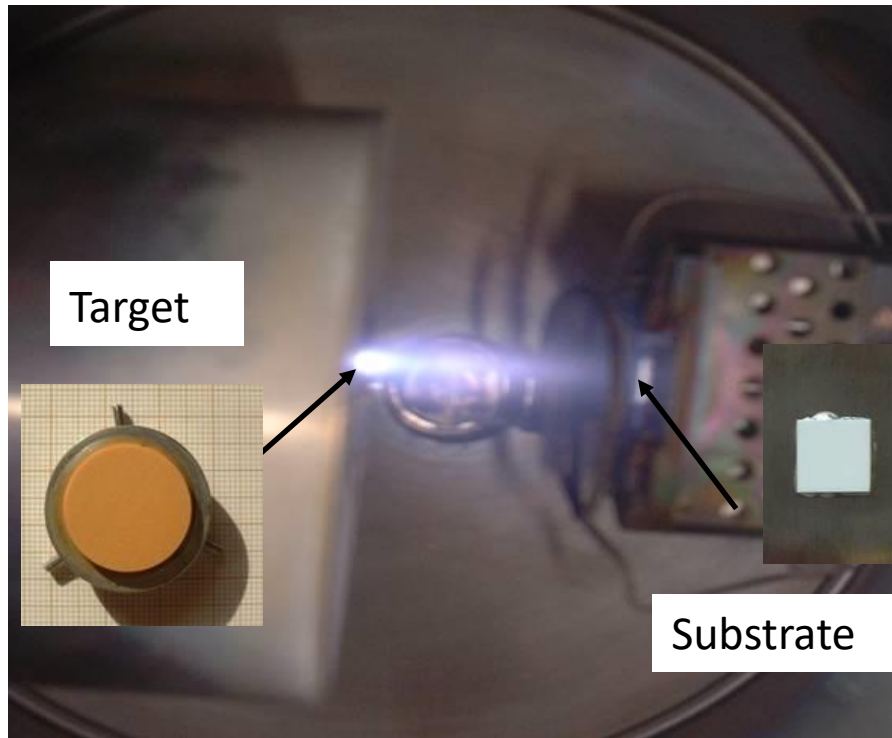
D. Dijkkamp, T. Venkatesan et al., Appl. Phys. Lett., **51** , 619 (1987)

Pulsed Laser Deposition system



Excimer laser KrF
 $\lambda = 248 \text{ nm}$
Pulses 20 ns, 2 Hz
Fluence 1 - 4 J/cm²

Pulsed Laser Deposition system

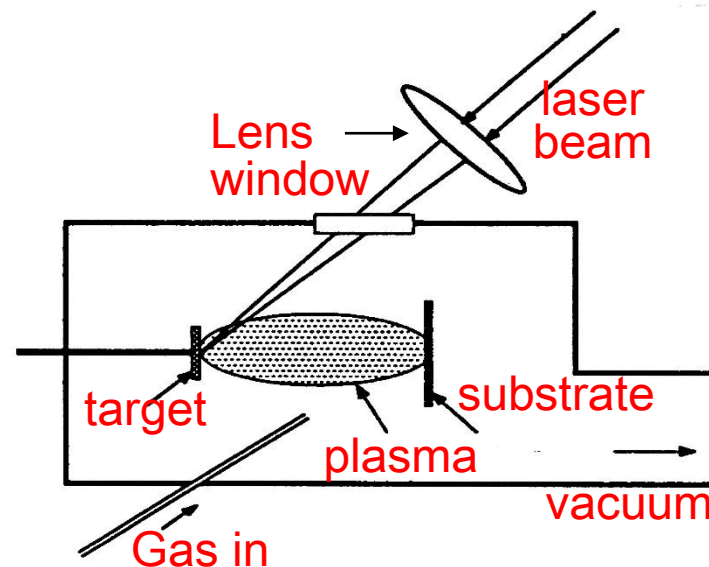
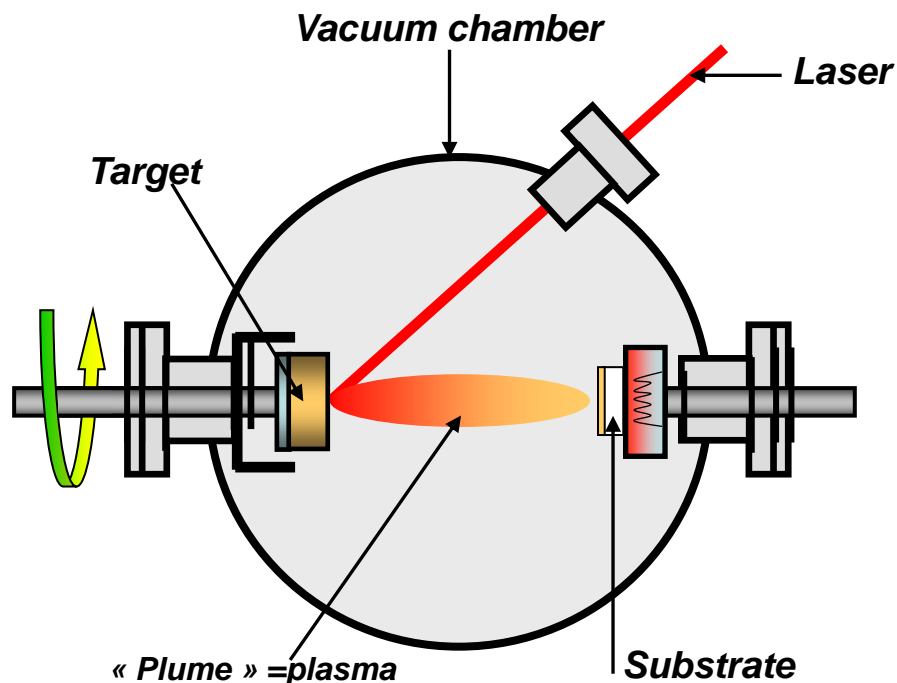


*Ceramic target by
Natural sintering
or SPS
Metallic foil
etc*

SPS Spark Plasma Sintering



PLD Principle



Excimer Laser XeCl (308nm),
ArF (193nm), Nd:YAG triple
(354nm)...

KrF - $\lambda = 248 \text{ nm}$

Pulses 20 ns, 1-3 Hz

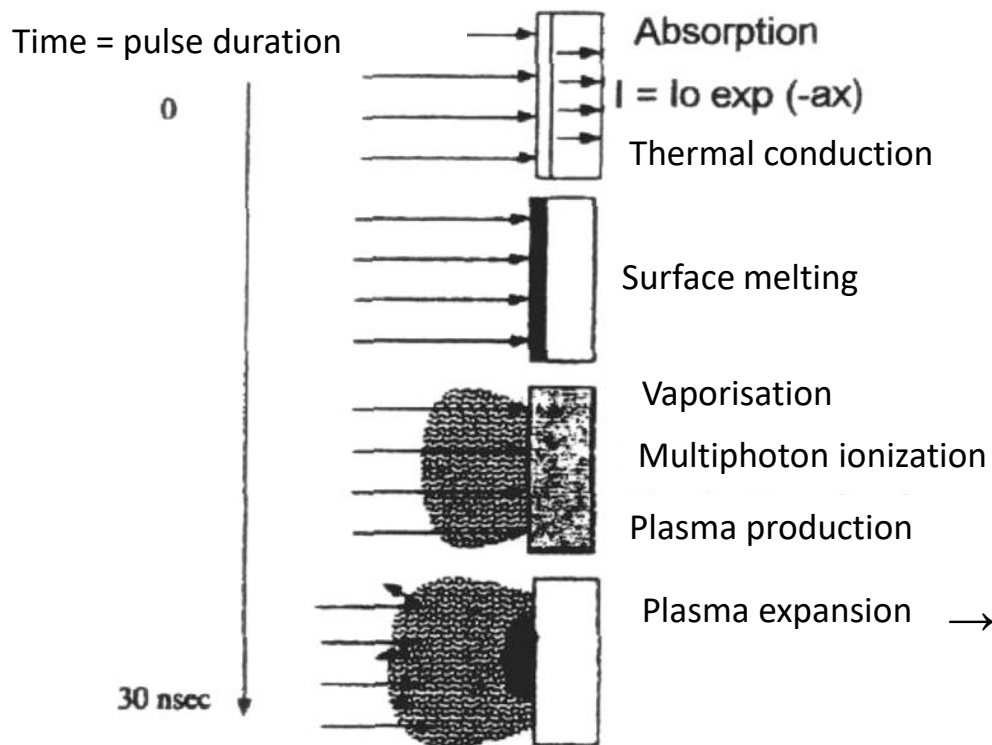
Fluence $\sim 2 - 3 \text{ J/cm}^2$

PLD Principle

- **Main parameters**
- **Laser:**
 - Wavelength
 - Pulse duration
 - Repetition rate (frequency)
 - Fluence: $E/\text{interaction surface on the target J/cm}^2$
- **Deposition conditions:**
 - Deposition temperature
 - Deposition atmosphere: pressure and nature of gas
 - Target / substrate separation
 -

Laser ablation principle

PLD



“Sublimation”



Melting then vaporization
 $T_{\max} \sim \text{several } 1000 \text{ K}$

→ the mechanism depends strongly on the material

→ 2 regimes

1- at low fluence: production of vapor \cong less dense environment

Main mechanisms: thermal conduction, melting, target vaporization

2- at high fluency : excitation and ionization

→ the incident laser beam is partially absorbed by the environment ;
plasma formation

Main mechanisms : the process is influenced by the laser-plasma
coupling and the plasma kinetic

→ evaporation process +

→ photoexcitation – photochemical effect, ionization, etc

→ Important role of the fluence

→ a threshold fluence for each material

Pulse duration

An important parameter: the pulse duration

- Most of studies: nanosecond (1- 40 ns mainly)
- pico- et femto-second
- If an extremely short pulse: thermal expansion more or less negligible
- femto- and pico-second: in 1st approximation : direct solid-vapor transfer (*in fact more complicated*)
- *Femto-second: athermic process*
- Case of standard nanosecond ablation of metals:

absorbed E heats the target up to T_m then T_{vap}

→ evaporation from the melting liquid

photon – target interaction

Laser wavelength

- *Depends on optical and thermal characteristics of the target :*
 - R : reflection coefficient
 - α : absorption coefficient
 - K : thermal diffusivity
- *Depends on the laser :*
 - wavelength: λ
 - Pulse duration: τ
 - Energy density on the target (= fluence): F

laser beam : a part is reflected by the target,
another part is absorbed

Laser beam absorption

Classical Beer-Lambert law

$$I(z) = I_0 \cdot (1 - R) \cdot e^{-\alpha(\lambda)z}$$

R : reflection coefficient

α : absorption coefficient

$I(z)$: wave intensity at z deep

I_0 : incident wave intensity

thickness of the target penetrated by the wave z_0 :

$$z_0 = \frac{1}{\alpha(\lambda)}$$

α : absorption coefficient in m^{-1} , cm^{-1}

R : reflection coefficient

- R depends on the electromagnetic wavelength: $R(\lambda)$
- R depends also:
 - On the electrical conductivity of the target material
 - On the target surface quality

K= target thermal diffusion coefficient (« diffusivity »)

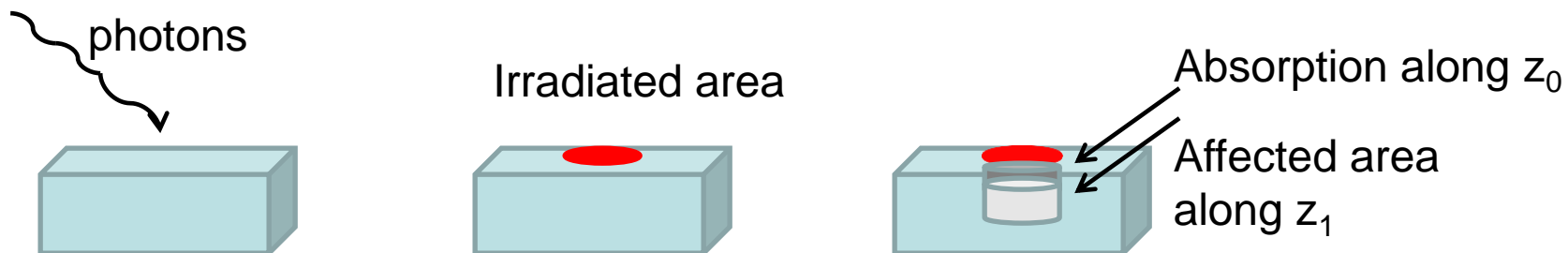
$$K = K_{th} / \rho C$$

K_{th} thermal conductivity, K_{th} : in $\text{W.m}^{-1} . \text{K}^{-1}$ and K : $\text{m}^2 \text{s}^{-1}$
 ρ volumic mass, C calorific capacity $\text{J.g}^{-1} . \text{K}^{-1}$ if ρ in g.m^{-3}

Depth affected by radiation in the target

- Estimation of the thickness of the target's layer thermally affected by the irradiation:

$$z_1 = \sqrt{(Kt)}$$



→ Depending on the material : z_1 may be larger than z_0 or close to z_0

Interest of a UV laser

- To limit thermal effect → short wavelength
→ most often: excimer laser with $\lambda < 500$ nm

ArF: 193 nm (excimer)
KrF: 248 nm (excimer)
Nd:YAG (solid) (1064 nm, 532 nm, 355 nm, 266 nm)
- Prerequisite: absorption of the laser beam by the target's material at this wavelength
→ high α
- + roughness of the polycrystalline target enables to increase absorption

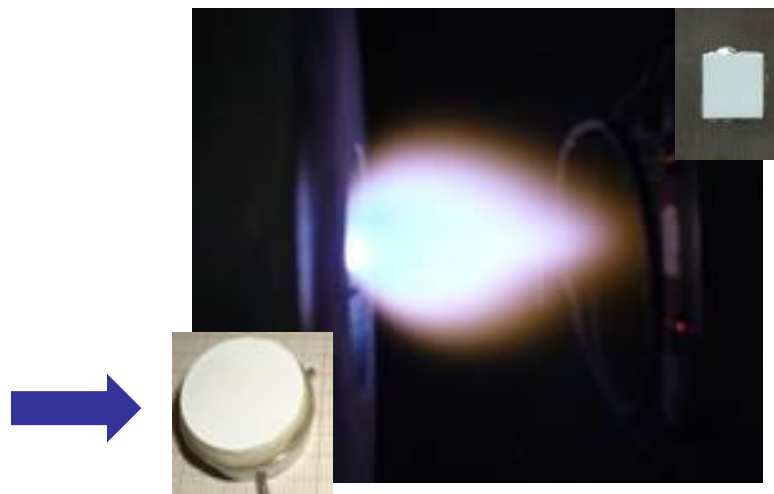
- Target irradiation can promote 2 phenomena:
 - Thermal evaporation
 - Photochemical interaction*in practice: both : i.e. an intermediate situation*

→ **PLD is not only evaporation**

- ➔ In all cases, to promote matter ejection: F has to be larger than a threshold value that depend on :
- λ , τ
 - target composition

Generally : 0,1- 2 J/cm² for oxides

A few tens of J/cm² for glassy carbon



Example of the ferroelectrics $\text{KTa}_{1-x}\text{Nb}_x\text{O}_3$ (KTN) and $\text{K}_x\text{Na}_{1-x}\text{NbO}_3$ (KNN)

Q. Simon et al., *Appl. Phys. Lett.* 99, 092904 (2011)

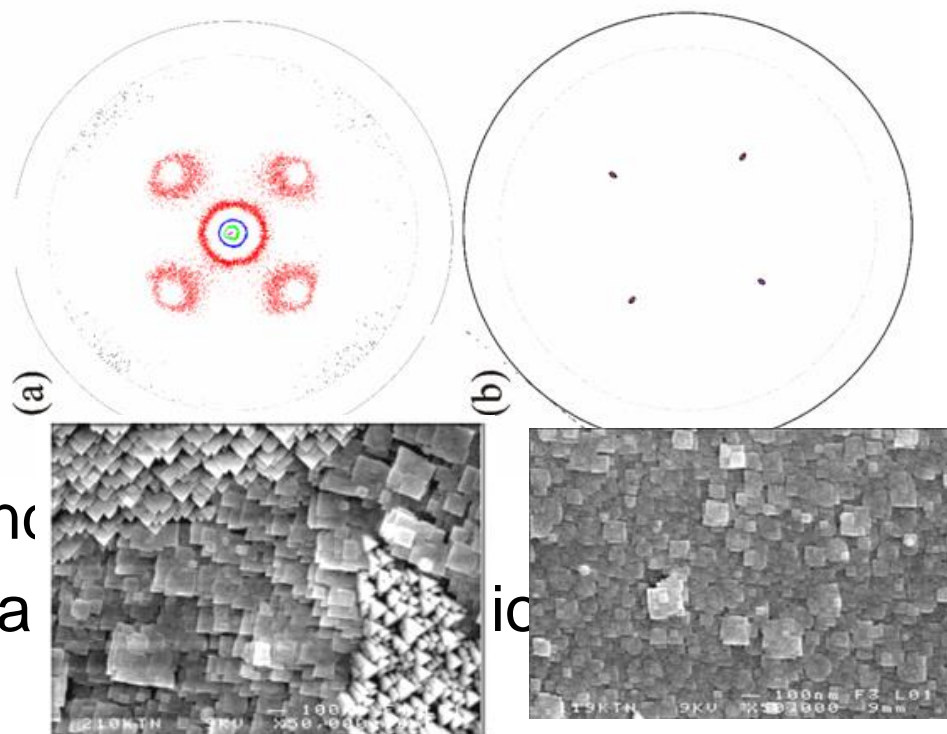
B. Aspe et al., *Journal of Alloys and Compounds* 827 (2020) 154341

B. Aspe, et al. *Journal of Alloys and Compounds*, 856 (2021) 158138

B. Aspe, et al. *IEEE Antennas and Wireless Propagation Letters*, 20 (2021), 1414-1418

Morphology of the film

- « Thin film »
- Nano-objects i.e. nanorods
→ role of the deposition concentration
→ importance of the material (i.e. crystalline structure)

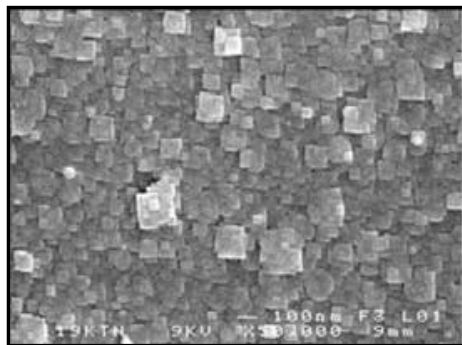
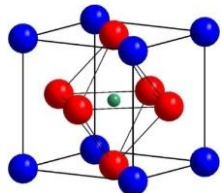


W. Peng, et al.

Integrated Ferroelectrics, 93, 126-132, (2007)

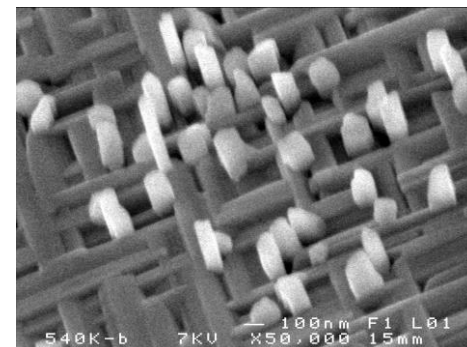
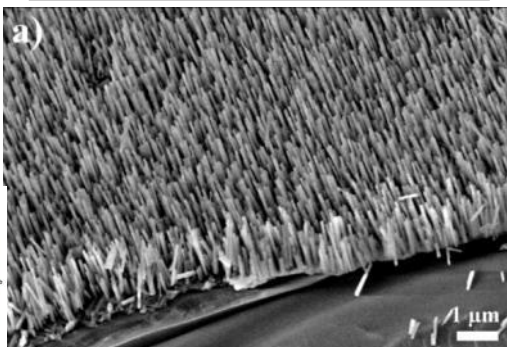
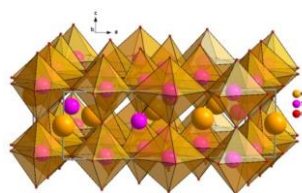
In the K-Ta-Nb-O system (piezoelectric phases) From perovskite to Tetragonal Tungsten Bronze (TTB) phase

Perovskite



→ From thin film to nanorods

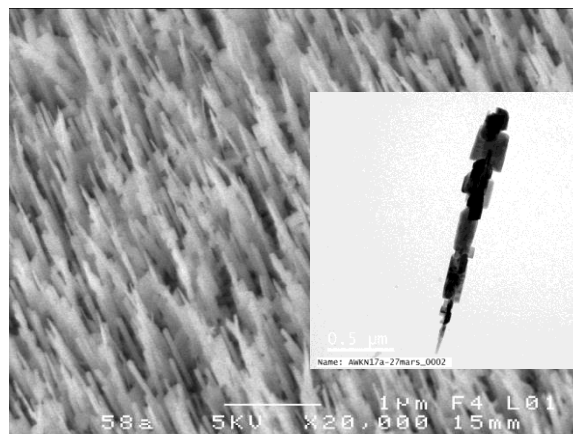
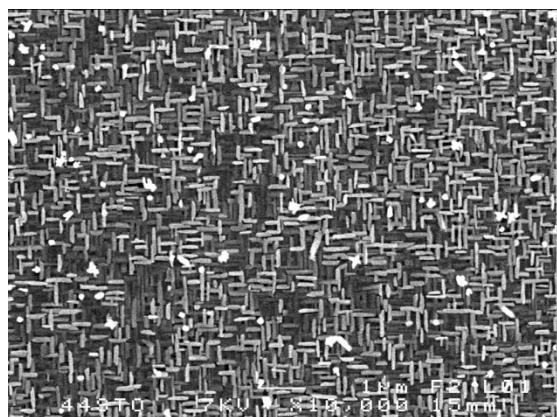
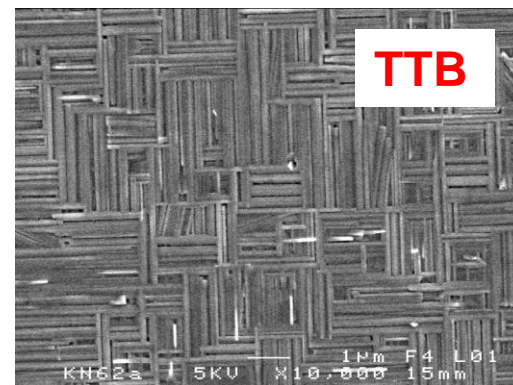
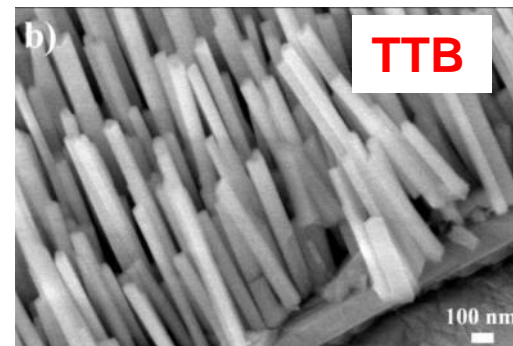
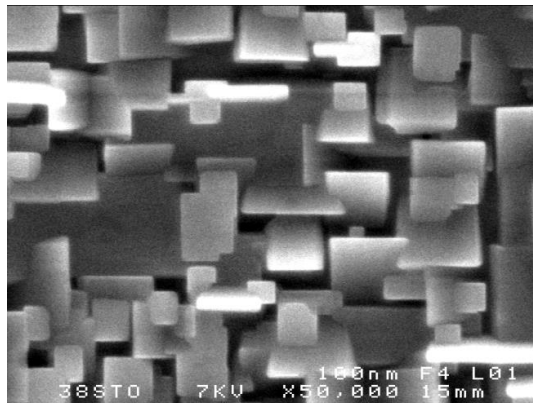
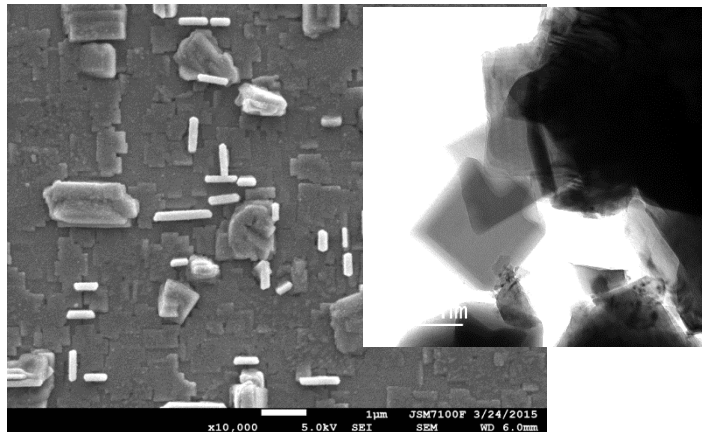
TTB



→ Variation of K content → variation of the crystalline phase
→ evolution of the morphology

Q. Simon, V. Dorcet, P. Boullay, V. Demange, S. Députier, V. Bouquet, M. Guilloux-Viry.
Chem. Mater. **25** (2013) 2793

Composition, structural and epitaxial effects



V. Demange, et al.
Crystal Growth & Design, 20 (2020) 2356-2366

Control of thin films composition

- Some examples to illustrate how to control the composition of multi-element materials in thin films by PLD
- PLD is well – known for the good transfer of composition, but it can vary with the target composition

BUT chemistry has to be taken into account

Superconducting $\text{YBa}_2\text{Cu}_3\text{O}_7$ (YBaCuO) thin films

- Stoichiometric targets \rightarrow near stoichiometric films (**no volatil cation**)
 - **$\text{YBa}_2\text{Cu}_3\text{O}_x$**
- Oxygen content controlled by deposition and cooling atmosphere :

P(O ₂)	deposition	cooling	T _c
	0.3 mbar	300 mbar	86-90 K
	~ 0.3 mbar	~ 0.3 mbar	~ 60-70 K

- Epitaxial thin films on various substrates

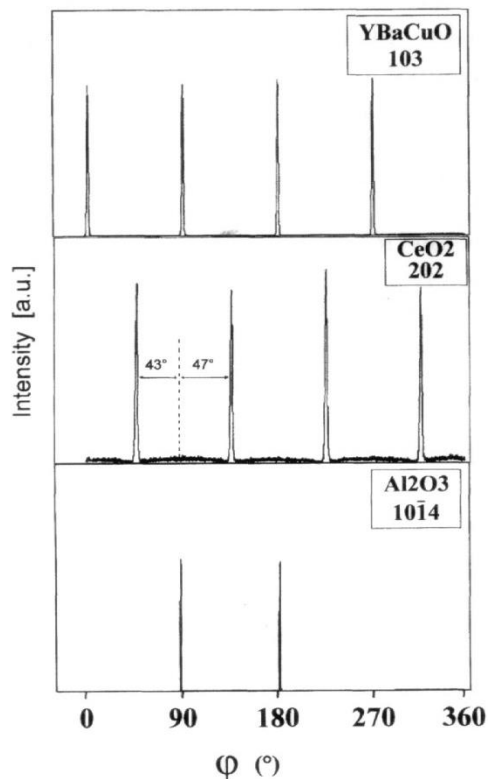
M. Guilloux-Viry et al. *J. Cryst. Growth*, 132, 396, (1993)

C. Perrin et al. *J. Alloys & Compounds*, 195, 339 (1993)

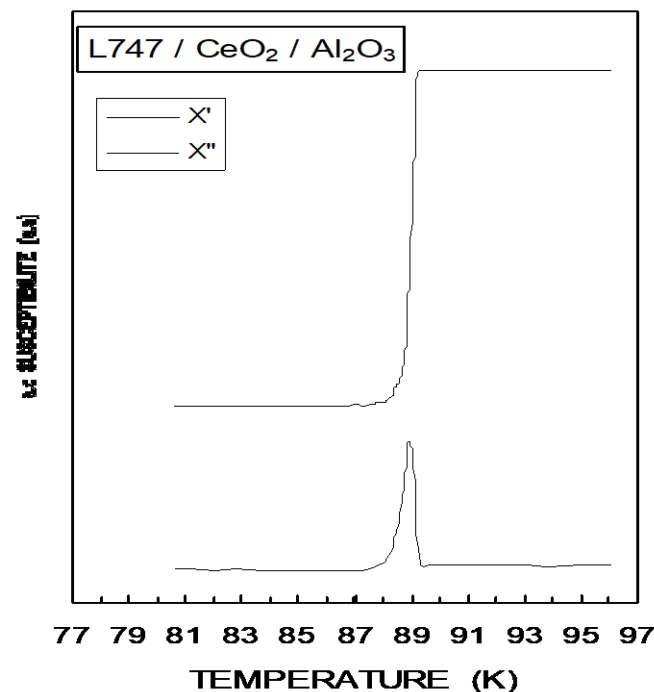
C-axis oriented $YBa_2Cu_3O_7$ epitaxial films on substrates suitable for microwaves

X-ray diffraction φ -scans

→ epitaxy on $CeO_2 / R-Al_2O_3$



On $CeO_2 / R-Al_2O_3$



$$R_s (10\text{GHz}, 77\text{ K}) = 0.5\text{-}1\text{ m}\Omega$$

C. Le Paven-Thivet et al. *Physica C*, 244, 231, (1995)

X. Castel et al. *J. of Crystal Growth*, 187, 211 (1998)

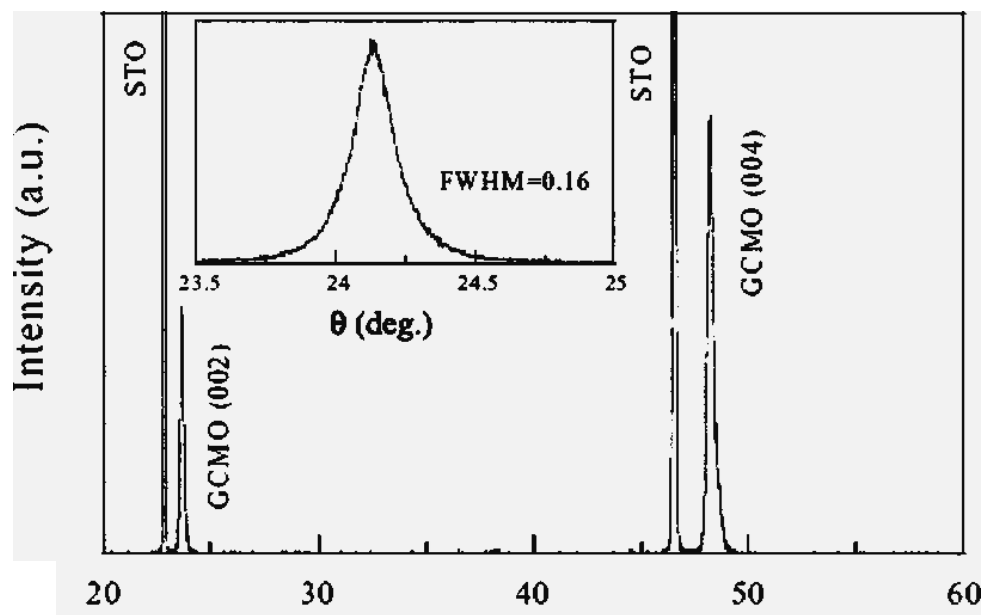
example without volatil cation → Magnetic oxides : $\text{Gd}_x\text{Ca}_{1-x}\text{MnO}_3$

- Stoichiometric target → stoichiometric films for cations
- Control of oxygen content with deposition pressure and post-annealing
- $T_d = 740^\circ \text{C}$, $P(\text{O}_2) = 0.2\text{-}0.6 \text{ mbar}$

Θ -2 θ X-ray diffraction

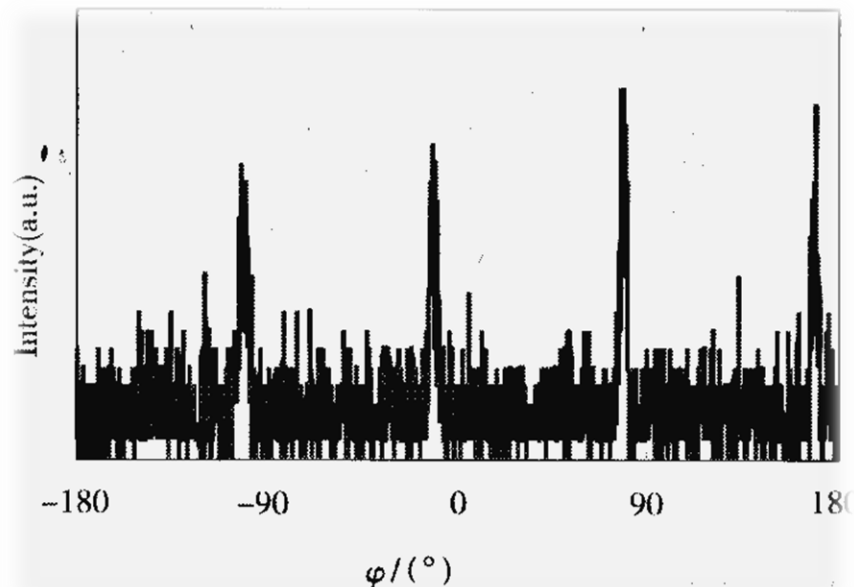
→ highly oriented films

Out of plane orientation



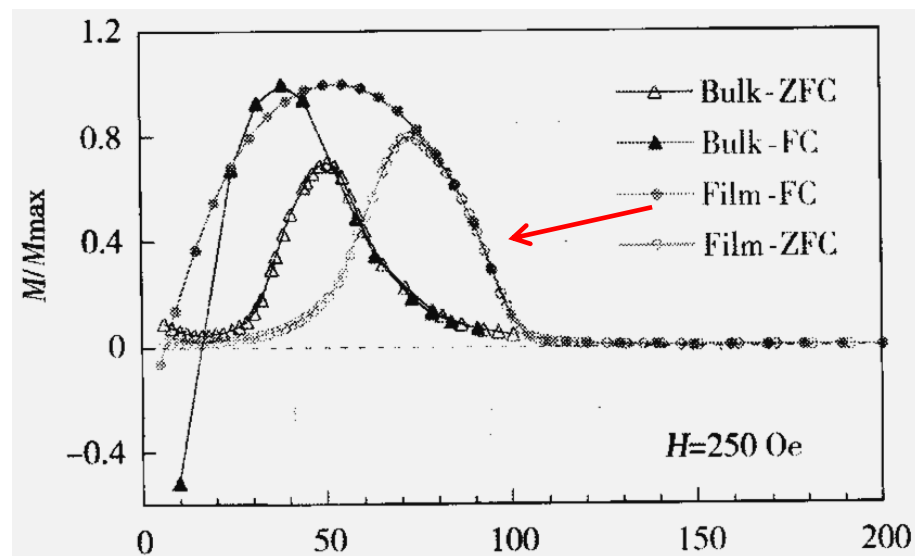
O. Peña, Y. Ma, M. Guilloux-Viry, C. Moure
Appl. Surf. Sci., doi : 10.1016/j.apsusc.2007.07.061, (2007)

Gd_{0.67}Ca_{0.33}MnO₃ thin films



- → Magnetic ordering

- XRD ϕ -scan → epitaxial growth
- In-plane orientation



Y. Ma, M. Guilloux-Viry, P. Barahona, O. Peña, C. Moure
Appl. Phys. Lett., **86**, 062506 (2005)

Functional oxides **containing volatil cations**: examples of ferroelectric materials

PbZr_{0.52}Ti_{0.48}O₃ simple perovskite structure

Sr**Bi**₂Nb₂O₉ layered perovskite-like structure

KTa_xNb_{1-x}O₃ perovskite structure – solid solution

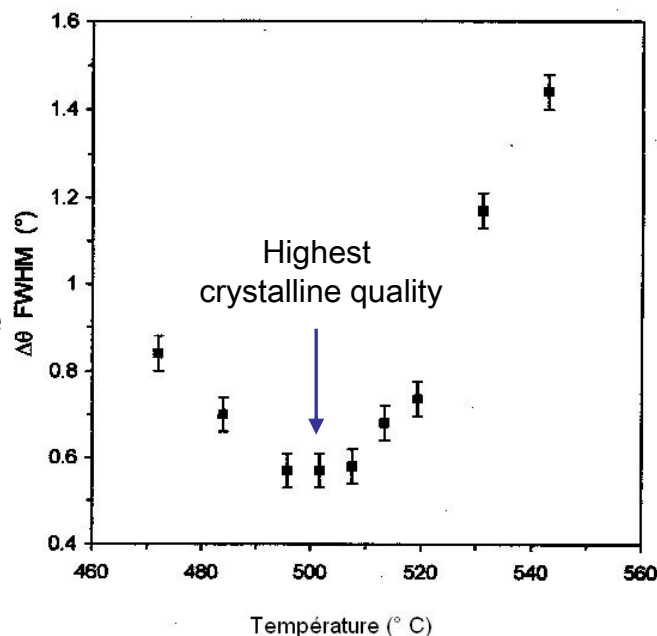
PbZr_xTi_{1-x}O₃ (PZT)

- **PbZr_xTi_{1-x}O₃** : deposition temperature compatible with composition ~ stoichiometry from a target slightly enriched in Pb

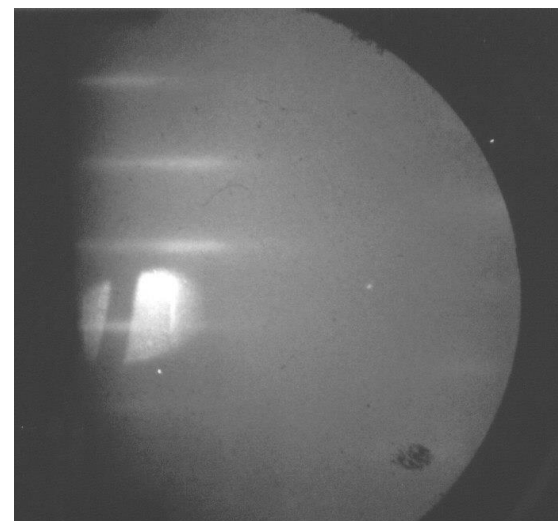
On (100)LiF

$$\Delta \theta = f(T_d)$$

FWHM rocking curve



RHEED → epitaxy

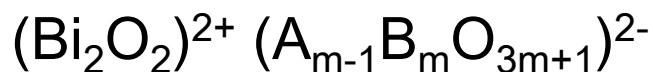


L'H. Hamedi, M. Guilloux-Viry, A. Perrin, G. Garry, *Thin Solid Films*, 352, 66 (1999)

SBN : $\text{SrBi}_2\text{Nb}_2\text{O}_9$

- layered structure « Aurivillius phase »
- orthorhombic structure : $a = 5.519 \text{ \AA}$, $b = 5.515 \text{ \AA}$, $c = 25.11 \text{ \AA}$

$$a(\text{SrTiO}_3) \times \sqrt{2} = 5.52 \text{ \AA} \quad \rightarrow \Delta a/a = 0.05 \%$$



$$m=2, \text{A}=\text{Sr}, \text{B}=\text{Nb}$$

Ferroelectric characteristics :

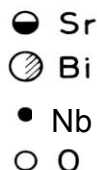
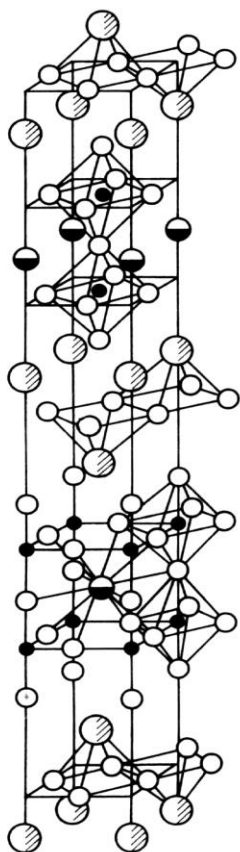
$$T_{\text{curie}} \sim 440^\circ \text{C}$$

$$P_r \sim 10 - 20 \text{ mC/cm}^2$$

$$E_c \sim 60 \text{ kV/cm}$$

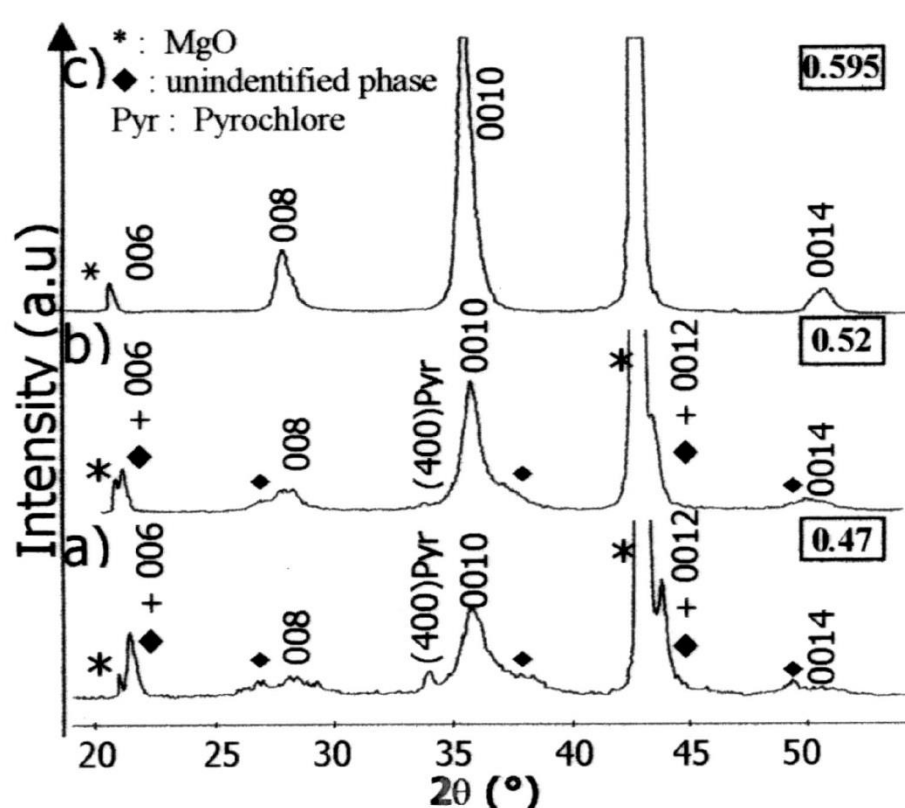
Polarisation : ab plane

Fatigue resistant



Deposition from Bi_2O_3 enriched Sr-Bi-Nb-O targets

At 700° C, $P(\text{O}_2) = 0.3$ mbar → Bi deficiency due to Bi volatility



Bi/(Sr+Nb)

+ 20 % Bi_2O_3

+10% Bi_2O_3

stoichiometric target

SBN + 30 % Bi_2O_3

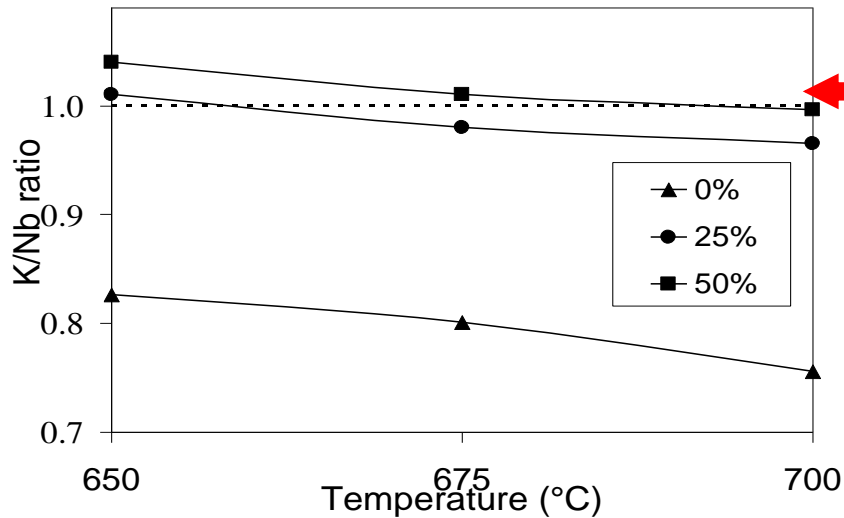
Stoichiometric epitaxial

$\text{SrBi}_2\text{Nb}_2\text{O}_9$ films grown at 700° C

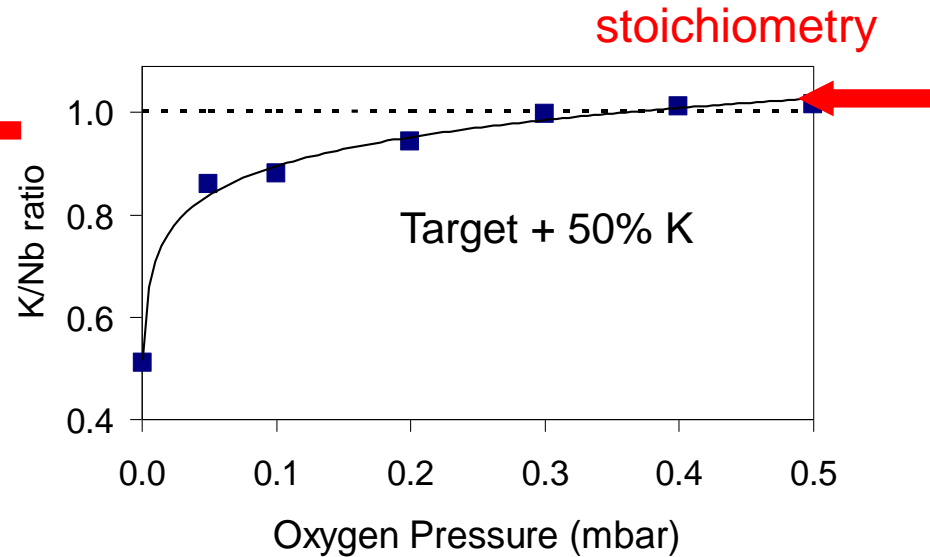
J.R. Duclère et al. *Appl. Phys. Lett.*, **83**, 5500 (2003)

Deposition of KNbO_3 and KTN from potassium enriched targets

$\text{K/Nb} = f(T_d) - P(\text{O}_2) = 0.3 \text{ mbar}$
3 different targets



$\text{K/Nb} = f(P(\text{O}_2)) - T_d = 700^\circ\text{C}$



Potassium enriched targets : + KNO_3 , molar content

→ $\text{K/Nb} = 1$: target + 50%, 0.3 mbar (O_2), 700°C

KTN → $\text{K}/(\text{Nb}+\text{Ta}) \sim 1$; $\text{Ta/Nb} (\text{film}) \sim \text{Ta/Nb} (\text{target})$

K volatility + K preferential backscattering during plasma expansion [M.J. Martín, et al J. Mater. Res., 12 (1997) 2699]

Thin films composition

Mo_6S_8 - $\text{Cu}_4\text{Mo}_6\text{S}_8$: solid solution

$\text{Cu}_2\text{Mo}_6\text{S}_8$, $\text{Cu}_3\text{Mo}_6\text{S}_8$:

→ superconducting material

→ insertion material ; potential interest as electrode for battery

PLD → films composition close to the target one

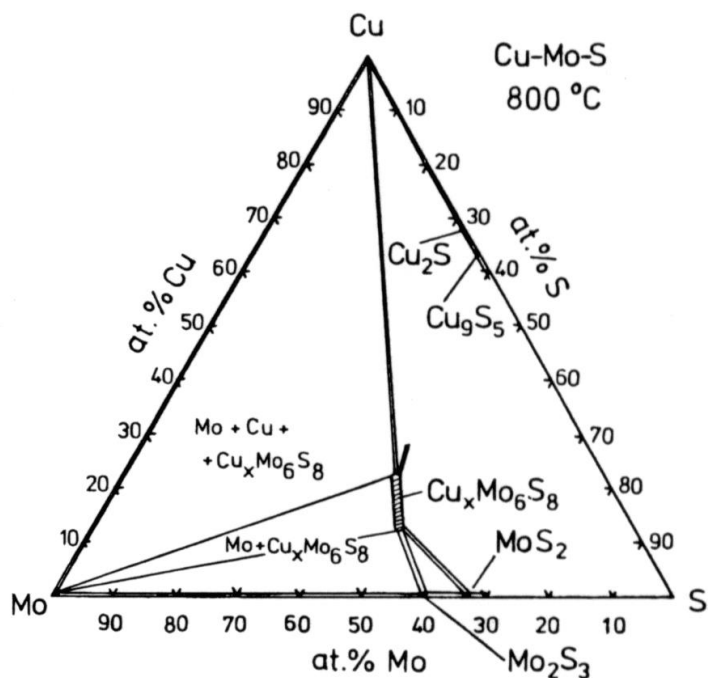
$\text{Cu}_4\text{Mo}_6\text{S}_8$:

→ semiconductor ; potential interest for thermoelectricity

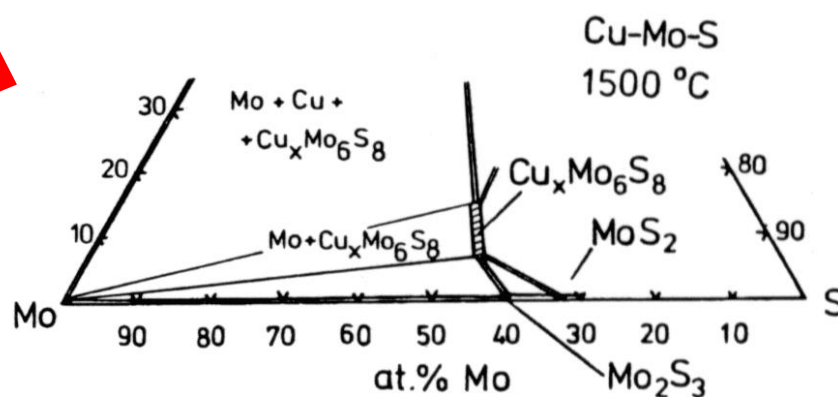
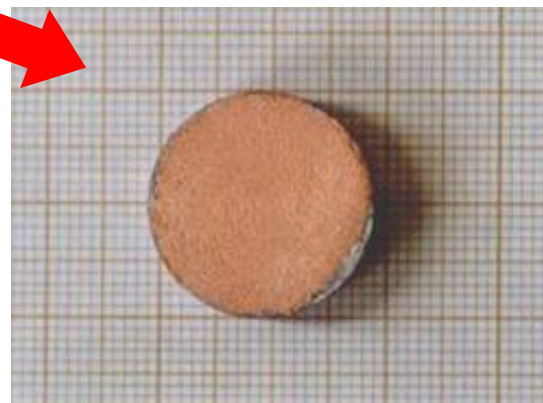
PLD → Cu and Cu_2S secondary phases (**very high excess of Cu**)

WHY ? → metastability of this composition

Expulsion of Cu : in relation with the metastability of $\text{Cu}_4\text{Mo}_6\text{S}_8$



(phase diagrams : R. Flükiger et al.)



PLD of high interest for the control of complex materials

- **High entropy oxide: an example**

Potential application in batteries (electrochemical reaction interfaces) and catalysis

“Growth of nanoporous high-entropy oxide thin films by pulsed laser deposition”

H. Guo, X. Wang, A.D. Dupuy, J.M. Schoenung, W. J. Bowman, J. of Mat. Res., 2022, 37 (1), 124

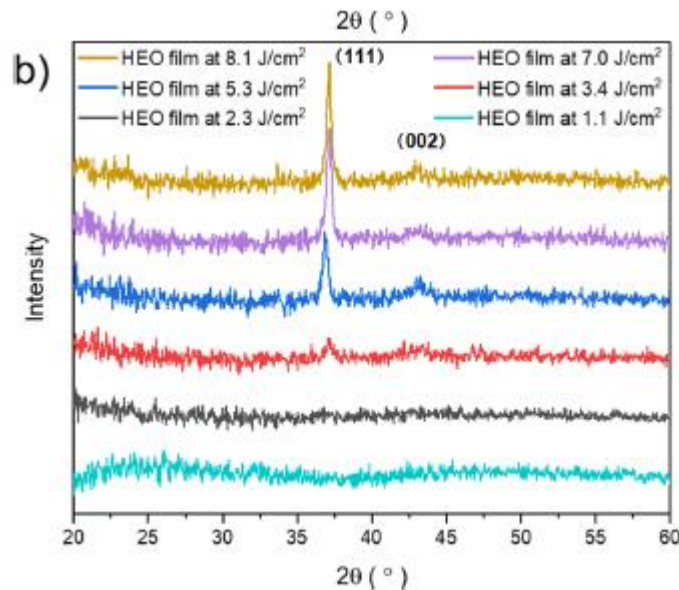
Ceramic target: $(\text{Co}_{0.2}\text{Ni}_{0.2}\text{Cu}_{0.2}\text{Mg}_{0.2}\text{Zn}_{0.2})\text{O}$

- PLD using Nd:YAG, with 266 nm, 10 ns
- ✓ PLD → 3D island morphology → nanoporous thin films
- ✓ Same structure as the target and homogeneous composition
- ✓ Study of the effect of the fluence:

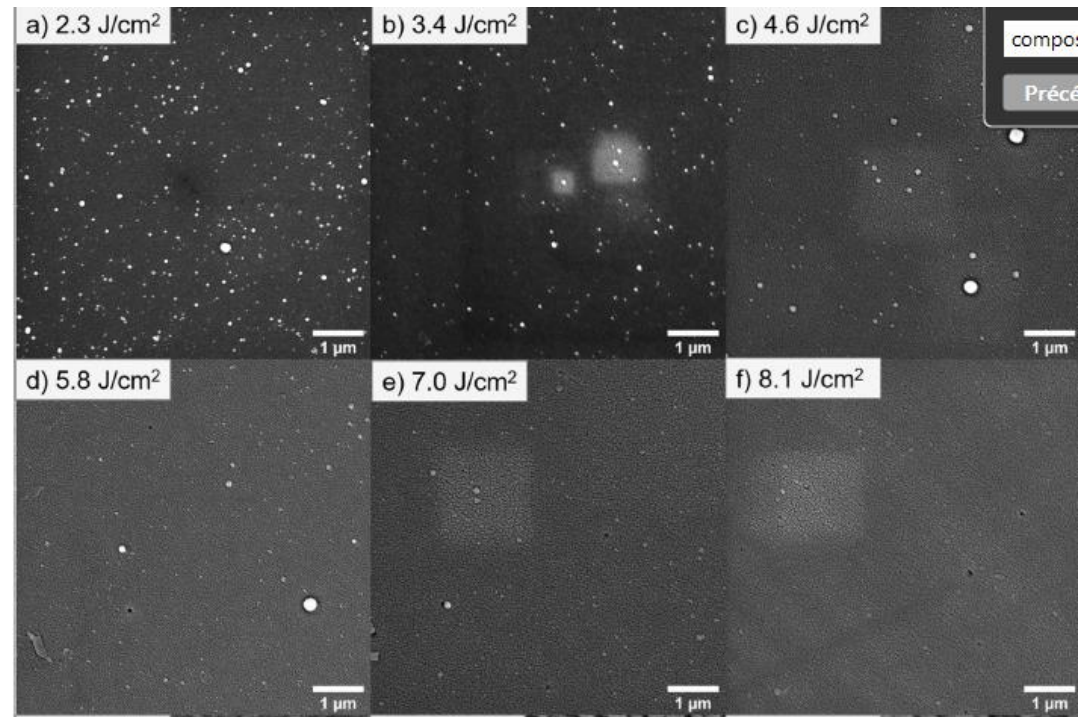
High entropy oxide

Increasing the fluence:

- Facilitates the crystallization
- Increases the thickness (60-140 nm)
- Influences the nanopores morphology and size
- Decreases the number of **droplets**



$$T_d = 300^\circ\text{C}$$



From “Growth of nanoporous high-entropy oxide thin films by pulsed laser deposition” , H. Guo, X. Wang, A.D. Dupuy, J.M. Schoenung, W. J. Bowman, J. of Mat. Res., 2022, 37 (1), 124

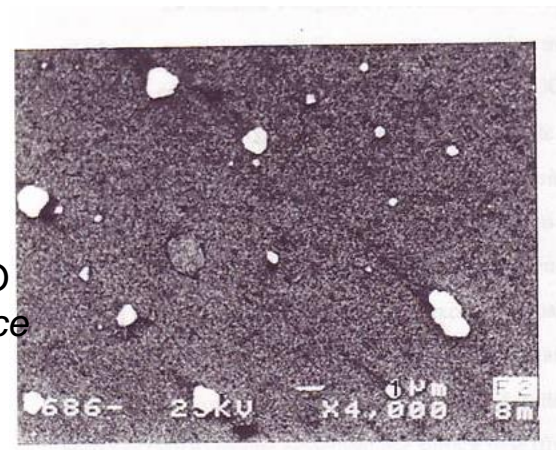
Droplets formation

At the edge of the vaporization area, the high temperature is not so high as in the center of this area but T is generally enough for melting
 → *creation of a melted bath*

At the violent plasma expansion, with the effect of the backward pressure: expulsion of droplets from the target that can arrive on the growing film

Droplets diameter: $\sim 1-5 \mu\text{m}$

Example: $\text{YBa}_2\text{Cu}_3\text{O}_7$ film on MgO
 Formation of droplets on the surface



→ High fluence, short wavelength, highly densified / sintered target contribute to reduce the number of droplets

→ ***Some illustrations of PLD in the context of nanomaterials for energy applications***

PLD combinatorial approach

Dr J. Wolfman



- Shadow mask between the substrate and the target → deposition in selected area on the substrate
- Targets selection, control of laser shots with one or two laser (dual PLD) to modulate the composition on the surface of the substrate

<https://greman.univ-tours.fr/english-version/research-topics/oxydes/combinatorial-and-dual-pld-thin-films-synthesis>

PLD combinatorial approach

Dr J. Wolfman
illustration



- *Electrical property modulation of Au/Ba_{0.6}Sr_{0.4}TiO₃/La_{0.7}Sr_{0.3}MnO₃ structure by continuous composition spread Mn doping*
J. Qiu, G. Liu, J. Wolfman, J. Xing, Ceramics International 48 (2022) 11786–11792
- Targets used for the BSTMx films in the Comb-PLD: BST and Ba_{0.6}→Sr_{0.4}Ti_{0.95}Mn_{0.05}O₃ (BSTM) ceramics.

→ PEPR DIADEM
Plate-forme μ ELEC

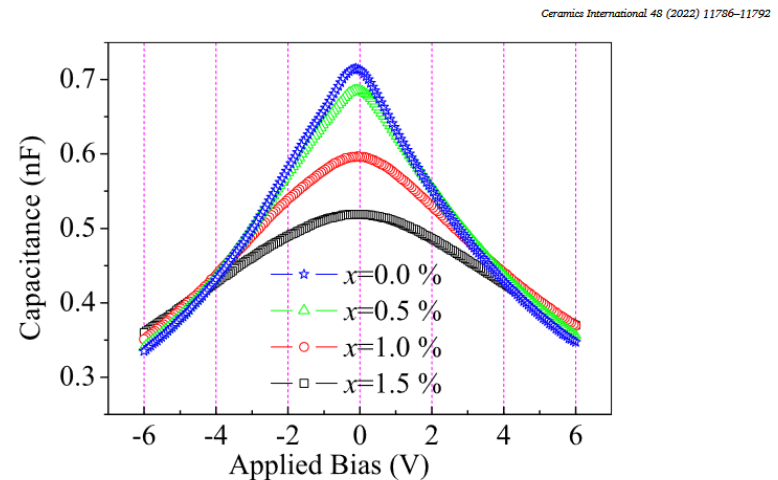


Fig. 3. The capacitance-bias curves of the Au/BSTMx/LSMO structure.

nanomaterials for energy applications

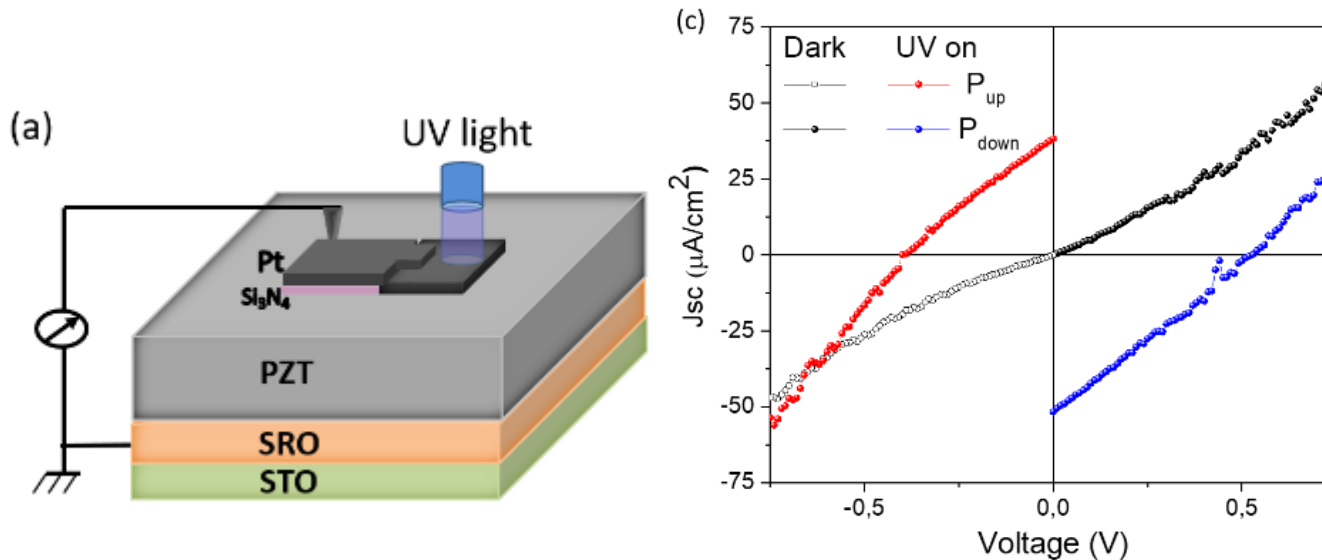
Quantitative investigation of polarization-dependent photocurrent in ferroelectric thin films

K. Rani, S. Matzen, S. Gable, T. Maroutian, G. Agnus, P. Lecoeur

Condensed Matter, 2021, 34 (10), pp.104003.



- Study of the switchability of the photocurrent according to the direction of the ferroelectric polarization



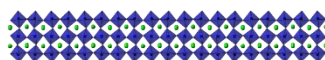
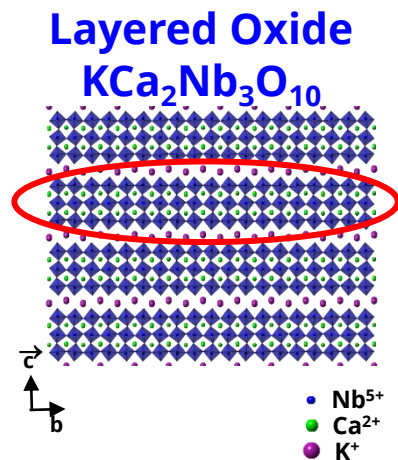
Epitaxial PZT (100 nm) thin films on 30 nm SrRuO₃
PLD: KrF excimer laser, 3J/cm² $P(\text{O}_2) = 120 \text{ mTorr}$, $T_d = 630^\circ\text{C}$

Integration of oxide functional thin films in devices requirements

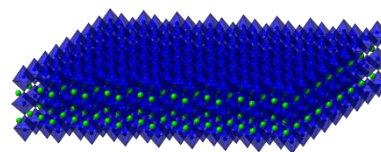
- High performance:
 - Cristalline quality
 - Properties suitable for the targeted application
 - Substrate: low cost, suitable for the growth of high quality thin films
- Possible limitations for oxides thin films:
 - Requirement of single crystal oxides substrate:
 - Cost
 - Limitation of large size availability
 - Thermal budget for the growth

Highly Transparent and Conductive Indium-Free Vanadates Crystallized at Reduced Temperature on Glass Using a 2D Transparent Nanosheet Seed Layer

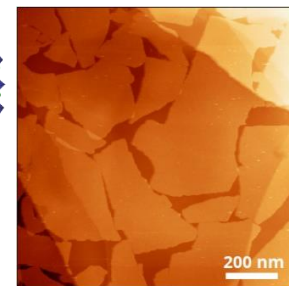
A. Boileau et al., *Adv. Funct. Mater.* **2021**, 2108047



Exfoliation
in solution



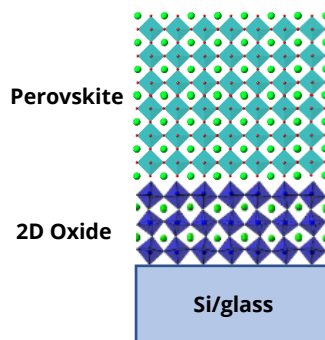
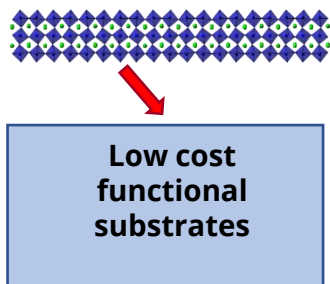
2D Oxides on Si



→ PEPR DIADEM
Plate-forme μELEC

ISCR (Rennes)
**Dr V.
Demange,**
CNRS

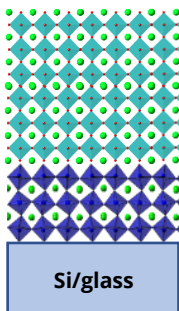
→ oxides nanosheets as germination layer for thin films
integration on various substrates (Si, glass, silica, flexible, ...)



anr® PolyNash (CRISMAT, ISCR, GEMAC)

Highly Transparent and Conductive Indium-Free Vanadates Crystallized at Reduced Temperature on Glass Using a 2D Transparent Nanosheet Seed Layer

A. Boileau et al., *Adv. Funct. Mater.* **2021**, 2108047

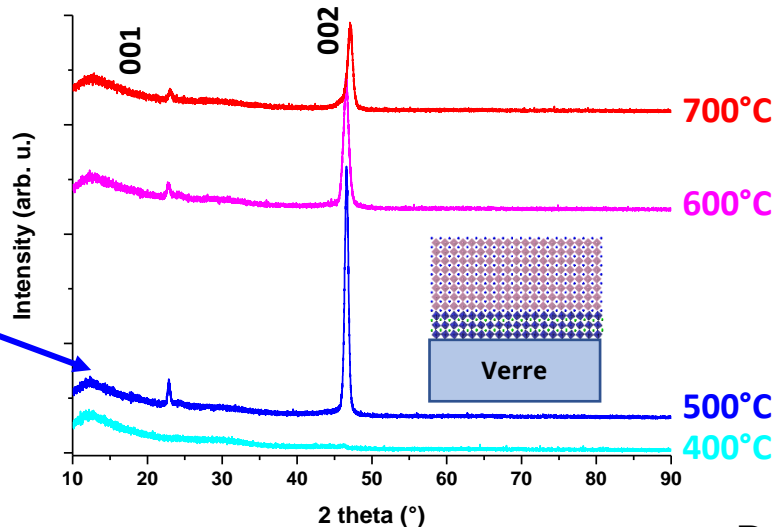


ISCR (Rennes)

Deposition by PLD of CaVO_3 or SrVO_3 layer (40 nm) by pulsed laser deposition (PLD) between 400 and 700 °C

SrVO_3 /glass :
Amorphous and
insulating

SrVO_3 /oxide nanosheets (2-3
nm) /glass :
cristallised, transparent and
conducting



GEMAC (Versailles)

Among the best TCO
@ $T_{\text{Growth}} = 500^\circ\text{C}$
 $\rho = 3.81 \times 10^{-4} \Omega \text{ cm}$
 $T > 70 \%$

Plasma expansion

- brutal plasma expansion
- brutal matter ejection towards areas with a lower local pressure
- pressure gradient = motive force
- the particles jet is then directional
- more directional than in classical evaporation methods

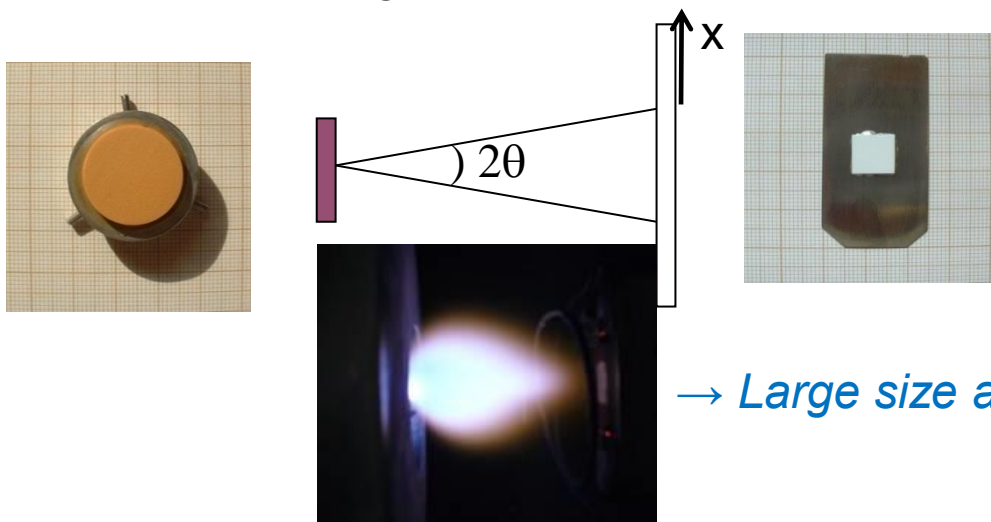


plasma expansion

- Acceleration along the normal at the target \gg to the one in the plane
→ *directional plasma*

Typical dimensions of the plasma formation at the laser beam – target impact:

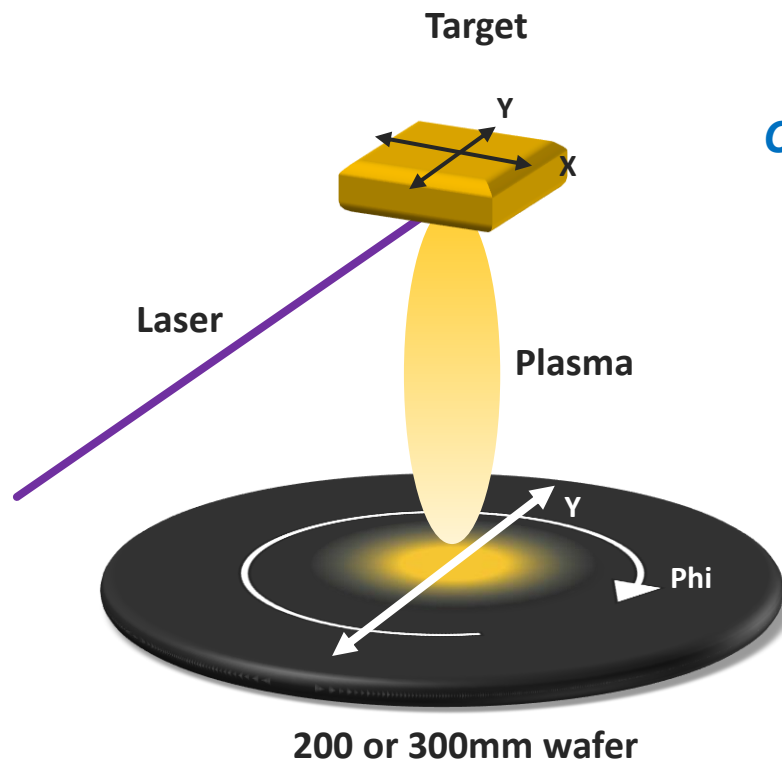
- // target (target plane): same dimensions as the laser spot (i.e: 1-2 mm²)
- along target thickness: $\sim 1-10 \mu\text{m}$
- Thickness distribution : $A\cos^4\theta + B\cos^n\theta$
- High value for n : $n \sim 7-20$: large thickness distribution along x



→ Large size area of deposition ?

Towards large area PLD thin films

Uniformity control on wafer area



Courtesy of Florian Dupont, CEA LETI

Deposition scan:

→ **Excellent thickness and stress uniformity** of deposited thin film

Towards large area PLD thin films

- SOLMATES 200 mm wafer PLD equipment at CEA LETI

Collaboration ISCR – CEA LETI (Dr G. Le Rhun) :
PhD Hugo KUENTZ (2020-2023)

Lead free piezoelectric transducers and reliability



ANR TILPAC (2023-2026) (Coord. Dr G. Le Rhun)

**Towards an Industry compatible high performances
Lead free Piezoelectric thin film material for MEMS
ACtuator applications**

***deposition of KNN on
200 mm wafer by PLD
at CEA LETI***



leti



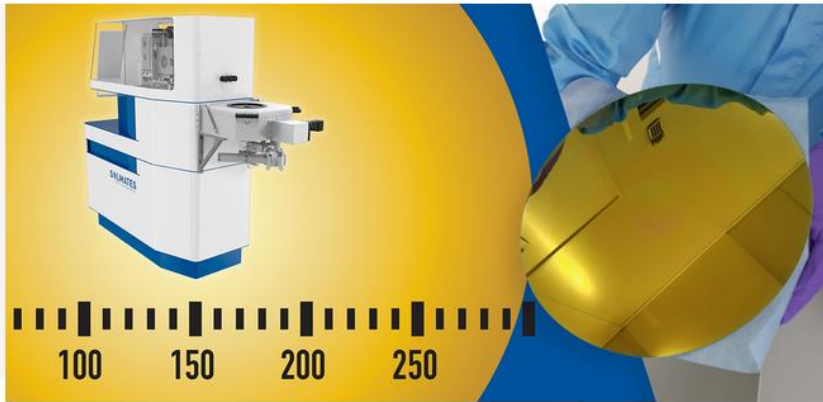
Institut des
Nanotechnologies
de Lyon UMR 5270



iemn
Institut d'Électronique, de Microélectronique
et de Nanotechnologie
UMR CNRS 9520

→ 300 mm wafer

<https://www.solmates-pld.com/about-us/history-of-solmates/>



Upscaling wafer size from 200 to 300 mm

We proudly showed our first ever 300 mm wafer coated by Solmates-PLD thin film equipment to the public. A small engineering step for Solmates, but a giant leap forward for thin-film manufacturing. Utilizing the intrinsic local nature of Pulsed Laser Deposition and innovative Solmates 'bridge tool' design, the scale-up from 200 to 300 mm was simply a matter of increasing the wafer scanning area, without the need for a larger target. This milestone was achieved at CEA-Leti and marks a bright future for PLD materials in automated 300 mm wafer device manufacturing.

SOLMATES
THIN FILM EQUIPMENT
A Lam Research Company



300mm deposition by PLD

PLD, from sample-scale to 300mm-compatible process

Concluding remarks

- PLD of high interest for deposition of multielement materials
- PLD suitable for nanomaterials elaboration for energy applications
- Evolution towards large size area wafer

→ *A specificity: kinetic energy during deposition*

Thin films growth – Crystallization

↕
deposition method

Crucial parameter
energy of particles on the surface of the substrate



Deposition process
→ E_k
(emitted particles)

**Deposition pressure
(atmosphere)**
→ ΔE_k

Substrate temperature :
 ΔE_k , diffusion ...

Specific features of PLD compared to other techniques

Technique	Energy (E_k)	Evaporation (MBE...)	Sputtering	PLD
Deposition process	Energy of emitted particles	$\sim 0.1 \text{ eV}$	$\sim 10\text{-}100 \text{ eV}$	$1\text{-}100 \text{ eV}$
Deposition pressure	Function of atmosphere nature $\rightarrow \Delta E_k$	ultra-high-vacuum $10^{-10} - 10^{-7} \text{ Torr}$	$10^{-3} - 10^{-1} \text{ Torr}$ E_k can decrease	<i>wide range</i> UHV to 10^{-1} Torr E_k can be maintained or can decrease

Concluding remarks

- PLD of high interest for deposition of multielement materials
- PLD suitable for nanomaterials elaboration for energy applications
- Evolution towards large size area wafer

→ *A specificity: kinetic energy during deposition*

- The chemistry and the cristalline structure of the material are always of first importance
- Not presented in this course: « MBE PLD » *cf Romain Bachelet presentation on MBE*

Acknowledgements

- ISCR : V. Demange, S. Deputier, V. Bouquet, S. Ollivier, C. Derouet, V. Le Cam, JL. Cercus



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V. Dorcet, L. Rault, Rennes University MET

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Thank you for your attention !